


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509616	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Alain L Bashore	<b>Art Unit</b>  1792

SEARCHED			
Class	Subclass	Date	Examiner
427	127, 128, 131, 132	3-27-08	ab

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (attached)	3-27-08	ab
Inventor and assignee search	3-27-08	ab
EAST (attached)	10-27-08	ab
previous search updated	10-27-08	ab
previous search updated	5-25-09	ab
east, npl (google scholar) updated	11/27/2009	ML
inventor, east, npl (google scholar) updated	8/14/2010	ML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/M. C. L./ Examiner.Art Unit 1792	/Alain L Bashore/ Primary Examiner.Art Unit 1792
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